

AMENDMENTS TO THE SPECIFICATION

Please amend paragraph 9 as follows:

[0009] A method for collecting measurements using a low capacitance measurement probe system. The method comprises disposing a low capacitance measurement probe in a designated area, directing an electrical current to the low capacitance measurement probe from control electronics, measuring electrical impedance between an inner conductor and an outer conductor of the low capacitance measurement probe to collect a first measurement, and directing measurement, and directing the first measurement to the control electronics.